Notice of References Cited Application/Control No. 10/751,731 Examiner Thomas D. Alunkal Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name ,	Classification
*	Α	US-5,732,062	03-1998	Yokoi et al.	369/116
*	В	US-6,343,062	01-2002	Furukawa et al.	369/275.4
*	Ċ	US-5,608,710	03-1997	Minemura et al.	369/47.51
	D	US-			
	Е	US-			
	F	US- '			
	O	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			`

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

	, test to the test of the test					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	х					

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.